

<b>Notice of References Cited</b>	Application/Control No. 10/622,744	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,561,620	10-1996	Chen et al.	365/185.3
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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